

An overview of PROBA-II and PROBA-V SEE analysis flow and comparison to in-flight data

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1 Company Introduction

Key Data

- Former Verhaert Space (name change April 2010 to QinetiQ Space)
- Founded in 1969 as product developer
- Space activities started in 1983
- Delivered 100+ systems and sub-systems for manned space stations, satellites and interplanetary missions
- Belgians leading space company and innovative product developer
- Acquired by the QinetiQ group (UK) in 2005
- 110 highly educated specialists employed in Belgium + 60 in Farnborough (UK space activ.)
- Turnover over 24 MEURO (2011 – Belgian activities only)



QinetiQ Space nv Headquarters

- Located in Kruibeke - Belgium
- Offices: 3.742 m², Warehouses: 1.200 m²
- 2 Class 100.000 cleanrooms



QinetiQ Space nv Ground Station Operations

- Located in Redu - Belgium
- ESA satellite ground station
- Jointly operated with SES Astra Techcom



QinetiQ Space UK

- Located in Farnborough - UK
- Integration Facilities
- Test Facilities



QinetiQ

QinetiQ Space nv

1 Company Introduction

QinetiQ Space

The leading provider of Small Space Systems

Satellites & Platforms



- Small satellite bus
- End-to-end mission solutions

Scientific Payloads



- Microgravity research
- Planetary exploration
- Earth observation
- Frequency Monitoring
- Metrology

Subsystems



- On-board computers
- Docking & Berthing Systems
- Space Mechanisms
- Electrical Propulsion
- UHF transponders

Downstream services



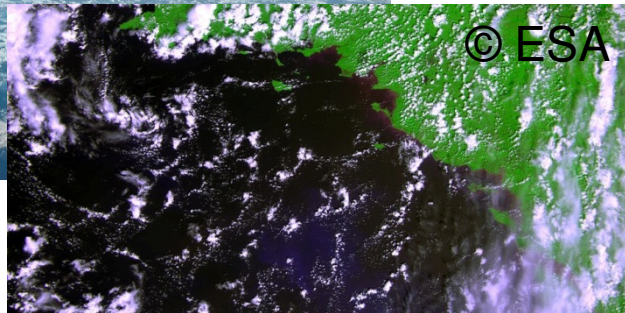
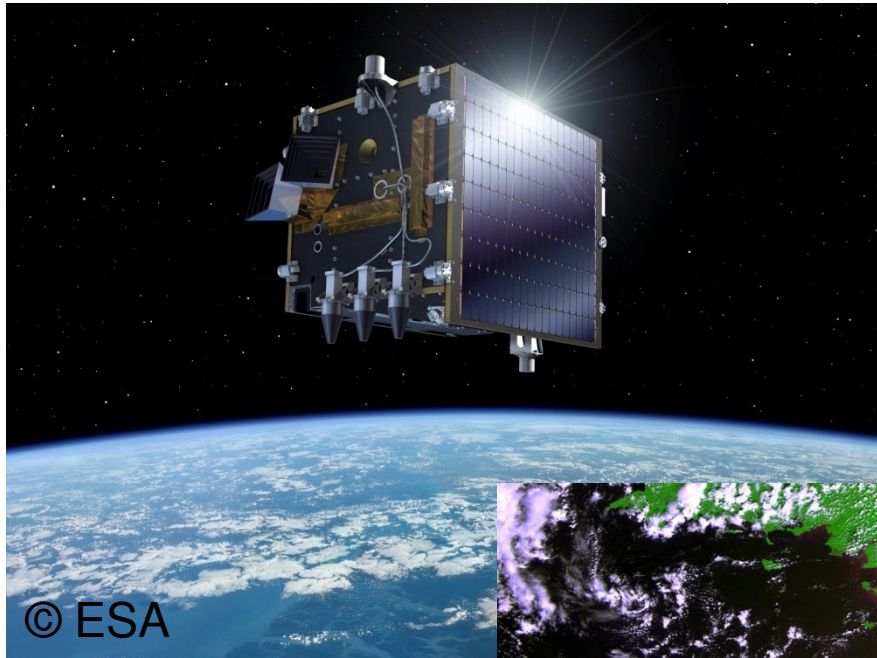
- Satellite Operations
- Integrated Applications
- Technical consultancy
- GIS applic & serv
- Space tourist training



QinetiQ

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2 Proba V Science Mission – Global Vegetation Growth



3 SEE Analysis setup

For all SEE components a radiation hardness analysis report is made. Critical components and circuits are analyzed and simulated in more detail. This includes SET pspice analysis, TID calculation, SEU/SET rate predictions and latchup protection simulation.

Spennis and Omere were used for PROBA-2 and PROBA-V to perform SEE rate and TID calculations.

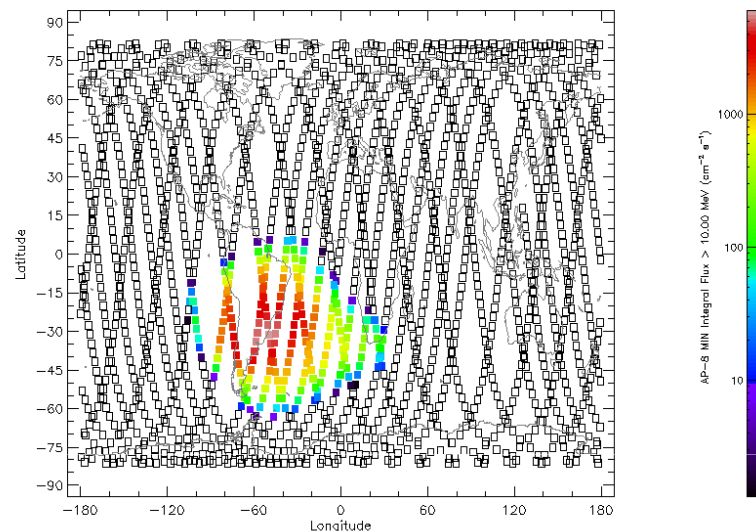
Radiation analysis inputs

- Mission requirements (examples)
 - Orbit definition (polar, appr. 800km)
 - Latchup threshold $>37\text{MeV}\cdot\text{cm}^2/\text{mg}$
 - Total dose 20Krad with standard shielding
- Models selection according to ECSS specs and ESA experts recommendations
 - Trapped particles: AE-8-MAX, AP-8-MIN
 - solar particles : ESP 95% confidence level
 - Cosmic Rays : GCR ISO or CREME96
- Component data availability
 - Hi-Rel parts with full characterization
 - Company characterization of commercial upscreensed parts
 - Historic data with sufficient level of detail

4 Orbit Definition

Basic parameters are straightforward and fixed but others are open to the user.

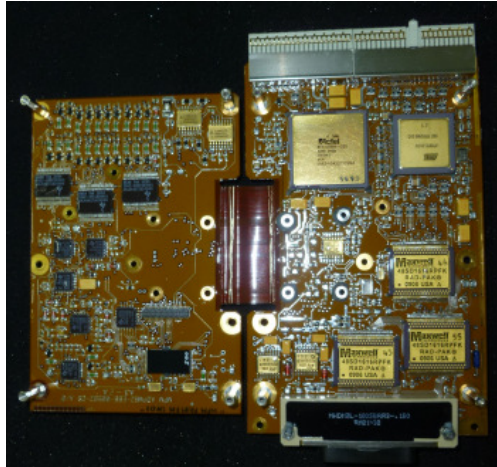
- Lots of different input possibilities!
- Use as many orbits as possible to have a good earth coverage. Maximum 20 in Spenvis, 100 used in Omere.
- Default output resolution is kept (60sec)
- Visualisation to ensure critical regions are passed in the correct ratio (poles, SAA crossings)
- For short duration calculations (e.g. SAA pass), TLE input with begin and end-time would be nice to have.



An error has occurred. Please check carefully your form inputs and correct the ones marked as wrong. Then resubmit your request.

Segment title:	
Orbit type:	two-line elements
Representative	number of orbits : 20 (100-1000) (MAX = 20.0)
First line:	1 36037J 09059B 13135.53072317 .00000224 00000-0 66118-4 0 1214
Second line:	2 36037 098.2967 328.0699 0012270 248 1293 130.1605 14.52367771 187274
Output resolution	
1.	60.0 s below 20000.0 km
2.	240.0 s below 80000.0 km
3.	3600.0 s elsewhere
<< Back Next >>	

5 ADPMS SEU analysis examples



K6R4016V1C SRAM (Samsung)

- Commercial upscreened part
- Radiation test reports publicly available
 - ESA_QCA103S_C (heavy-ions and protons)
 - ESA_QCA103T_C (total dose)

48SD1616RPFK SDRAM (Maxwell)

- Class K, Hi-Rel screened device
 - RAD-PAK, total dose >100krad (Si)
 - No latchup : $SEL_{TH} > 85 \text{ MeV.cm}^2/\text{mg}$ @25°C
 - SEE characterized by manufacturer
- Radhard does NOT mean insensitive to SEU, SEFI, stuck bits...

M29F032D70N6 FLASH (ST Microelectronics)

- Commercial upscreened part
- Limited public data with lack of details for analysis
- Flight lot was radiation characterised by QinetiQ Space
 - Total dose testing
 - Heavy Ion and Proton SEU, SEFI an SEL testing

6 Component data input

Initial analysis goal is to get a worst case behaviour to configure scrubber rates, implement SEFI recovery procedures and latchup protections.

But test reports don't give all the data!

- Sensitive volume
 - Area deduced from saturated cross-section
 - Sensitive depth in most cases unknown
- Error margins can be huge
 - Only few parts tested
 - Variations between test houses, reports
- Weibull fit or experimental data for both heavy-ions and protons are preferred
- SIMPA and PROFIT to be used with caution

PARTICLE ENVIRONMENT		
<input checked="" type="checkbox"/>	solar particles	
<input checked="" type="checkbox"/>	trapped protons	
<input checked="" type="checkbox"/>	GCR particles	
shielding thickness (Al equivalent):		1 g/cm2
number of devices:		4
Device 1: defined	K6R4008V1C_SEU (SI)	edit
Device 2: defined	48SD1616RPFK (SI)	edit
Device 3: defined	M29F032D70N6_MBU (SI)	edit
Device 4: defined	M29F032D70N6_SEFI (SI)	edit

Device material:	Si (SRIM2008)
Device source:	user defined
Device name:	K6R4008V1C_SEU
Shape Sensitive Volume: rectangular parallelepiped	
Dimensions: <input checked="" type="radio"/> 0.99 x 0.99 x 2.0 [µm]	
<input type="radio"/> 1450 x 2.0 [µm]	
Direct ionisation upset rates	
Cross-section method:	Weibull function
S:	2.15
L ₀ [MeV·cm ² /mg]:	0.84
W [MeV·cm ² /mg]:	32.24
σ _{lim} [cm ² /bit]:	9.99e-9
Algorithm:	constant LET (CREME)
Proton induced upset rates	
Cross-section method:	Weibull function
S _p :	0.69
E _{0,p} [MeV]:	7.30
W _p [MeV]:	26.27
σ _{lim,p} [cm ² /bit]:	9.19e-15

7 Proba-II in flight data

Prior to the PROBA-V launch, comparison between Proba-II in flight data and Spenvis/Omere calculations was possible.

- SRAM upsets are overestimated
 - 250 SEUs expected, only 4 seen per device
 - Scrubber / EDAC clears single bit errors
 - Simulated shielding is very conservative (3.7mm Al)
- Flash does not show any upsets
 - as expected, not sensitive to protons
 - Results are per device!
- SDRAM seems more sensitive
 - Expected rate is only 2 events during the mission
 - 2457 single bit errors since launch
 - Mainly on a few addresses, not random

Device	Effect	(bit ⁻¹)
K6R4008V1C	Direct ionization	5.0858E-07
	Proton induced ionization	2.9351E-05
	Total	2.9860E-05
48SD1616RPFK	Direct ionization	5.7033E-12
	Proton induced ionization	7.0378E-09
	Total	7.0435E-09
M29F032D70N6_MBU	Direct ionization	3.0455E-02
	Total	3.0455E-02
M29F032D70N6_SEFI	Direct ionization	1.2381E-01
	Total	1.2381E-01

8 Future analysis

- During analysis, GEANT4 tools were not yet used
 - Not yet a good overview of possibilities
 - Explore sectorial analysis
 - Effect of graded shielding
- Omere / Spenvis
 - Differences in results, mostly very minor (TID, heavy ion upsets)
 - Proton upset rates mismatch, under investigation (parameter settings?)
- Component input
 - Gathering and extracting relevant data from more radiation reports
 - Expected error/safety margins for simulation results
 - More component details (DIE structure, sensitive depth, areas) are needed

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